Corrigendum: Atomically resolved imaging of highly ordered alternating fluorinated graphene

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In the Methods section of this Article, the details of the STEM equipment and operating parameters used for the EELS studies were provided incorrectly. The following are the correct details: 'EELS studies were also performed on partially fluorinated graphene samples at the SuperSTEM Laboratory on a Nion UltraSTEM100 dedicated ultrahigh vacuum scanning transmission electron microscope equipped with a cold field emission gun with a native energy spread of 0.3–0.35 eV and operating at 60 keV.'